

Analog Integrated Circuit Design and Applications Spring 2024

Nonlinearity and Mismatch

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MSIC Lab

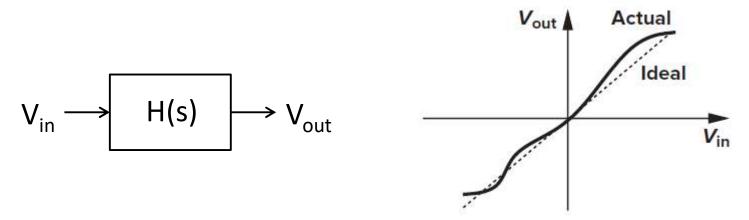
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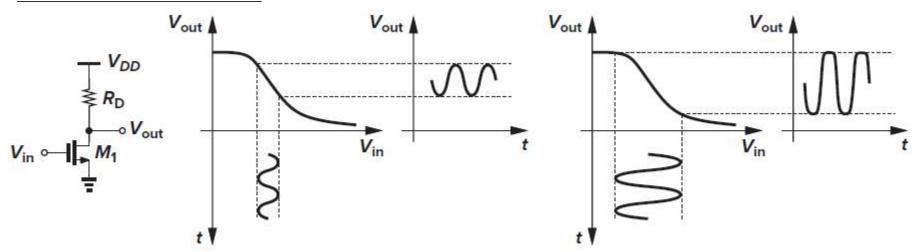
Outline

- Nonlinearity
 - THD: Total Harmonic Distortion
 - Linearization Techniques
- Mismatch
 - Random Mismatch
 - Systematic Mismatch
 - Input-Referred Offset
 - Current Mirror Deviation
 - THD Degradation
- Noise

Nonlinearity

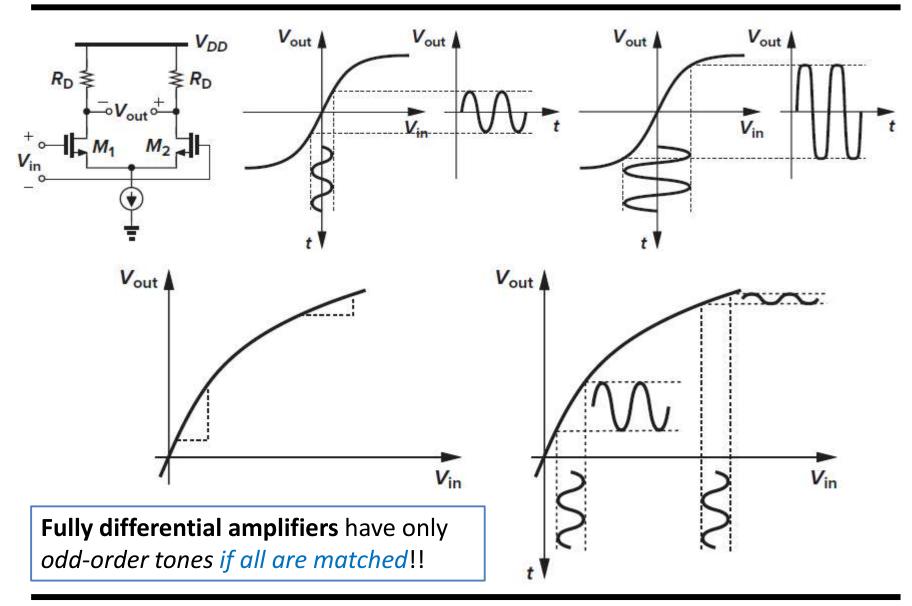


Single-ended amplifier



Nonlinearity: the amplifier gain is not constant but varies with the input amplitude

Nonlinearity



Total Harmonic Distortion (THD)

$$y(t) = \alpha_1 x(t) + \alpha_2 x^2(t) + \alpha_3 x^3(t) + \cdots$$

Input: $x(t) = A \cos \omega t$

$$y(t) = \alpha_1 A \cos \omega t + \alpha_2 A^2 \cos^2 \omega t + \alpha_3 \cos^3 \omega t + \cdots$$

$$= \underline{\alpha_1 A} \cos \omega t + \frac{\alpha_2 A^2}{2} [1 + \cos(2\omega t)] + \underline{\frac{\alpha_3 A^3}{4}} [3 \cos \omega t + \cos(3\omega t)] + \cdots$$

$$= \underline{\frac{\alpha_2 A^2}{2}} + \left(\alpha_1 A + \frac{3\alpha_3 A^3}{4}\right) \cos \omega t + \frac{\alpha_2 A^2}{2} \cos 2\omega t + \frac{\alpha_3 A^3}{4} \cos 3\omega t$$

If considering only HD2 and HD3, THD = HD2+HD3 is

Single-ended: THD =
$$\frac{(\alpha_2 A^2/2)^2 + (\alpha_3 A^3/4)^2}{(\alpha_1 A + 3\alpha_3 A^3/4)^2}$$

Harmonic distortion is undesirable in most signal processing applications, including audio and video systems. High-quality audio products such as compact disc (CD) players require a THD of about 0.01% (–80 dB), and video products, about 0.1% (–60 dB).

Distortion of Differential Amplifiers

$$x_{1}(t) \circ y_{1}(t)$$

$$x_{2}(t) \circ y_{2}(t)$$

$$y_{1} - y_{2} = (\alpha_{1}x_{1} - \beta_{1}x_{2}) + (\alpha_{2}x_{1}^{2} - \beta_{2}x_{2}^{2}) + (\alpha_{3}x_{1}^{3} - \beta_{3}x_{2}^{3})$$
Assume $x_{1} = x$ and $x_{2} = -x$,
$$y_{d} = y_{1} - y_{2} = (\alpha_{1} + \beta_{1})x + (\alpha_{2} - \beta_{2})x^{2} + (\alpha_{3} + \beta_{3})x^{3}$$
if $\alpha_{i} = \beta_{i}$, $\forall i \Rightarrow y_{d} = 2\alpha_{1}x + 2\alpha_{3}x^{3}$

- Single-ended signals have tones of 2nd, 3rd, 4th, ...
- Differential signals only have odd-order tones, ideally
- However, the mismatch causes even-order tones in differential signals
- In addition, thermal gradient also contributes mismatch

Harmonic Distortion: Single-ended

$$|A_{v}| \approx g_{m}R_{D} \qquad \text{DC operating point}$$

$$= \mu_{n}C_{ox}\frac{W}{L}(V_{GS} - V_{TH})R_{D}$$

$$I_{D0} = \frac{1}{2}\mu_{n}C_{ox}\frac{W}{L}(V_{GS} - V_{TH} + V_{m}\cos\omega t)^{2} \longrightarrow \text{Input signal}$$

$$= \frac{1}{2}\mu_{n}C_{ox}\frac{W}{L}(V_{GS} - V_{TH})^{2} + \mu_{n}C_{ox}\frac{W}{L}(V_{GS} - V_{TH})V_{m}\cos\omega t$$

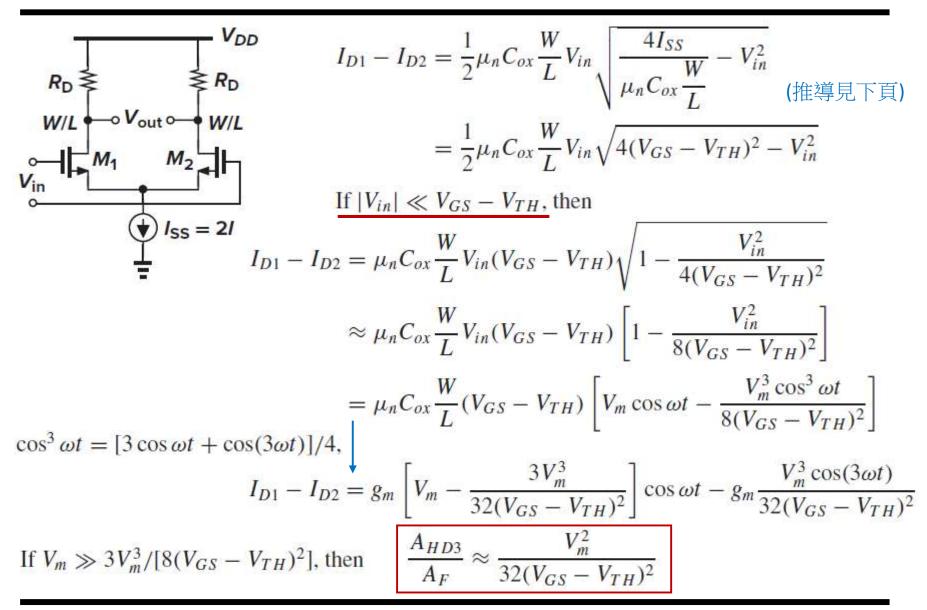
$$+ \frac{1}{2}\mu_{n}C_{ox}\frac{W}{L}V_{m}^{2}\cos^{2}\omega t$$

$$= I + \mu_{n}C_{ox}\frac{W}{L}(V_{GS} - V_{TH})V_{m}\cos\omega t + \frac{1}{4}\mu_{n}C_{ox}\frac{W}{L}V_{m}^{2}[1 + \cos(2\omega t)]$$

$$A_{F}$$

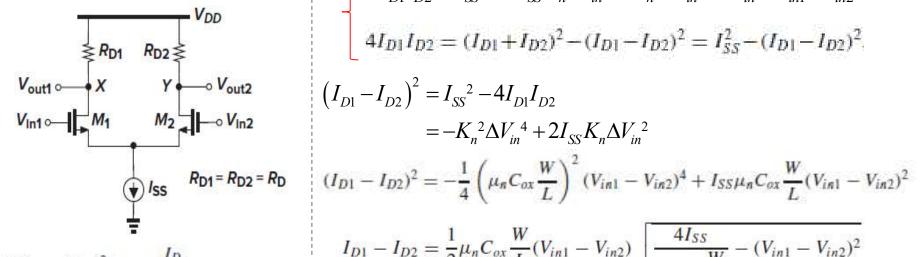
$$rac{A_{HD2}}{A_F} = rac{V_m}{4(V_{GS} - V_{TH})}$$
 (A very simple version)

Harmonic Distortion: Differential Pair



Harmonic Distortion: Differential Pair

g_m vs ΔV_{in} 推導之補充



$$(V_{GS} - V_{TH})^2 = \frac{I_D}{\frac{1}{2}\mu_n C_{ox} \frac{W}{L}}$$

$$V_{GS} = \sqrt{\frac{2I_D}{\mu_n C_{ox} \frac{W}{L}}} + V_{TH}$$

$$V_{in1} - V_{in2} = \sqrt{\frac{2I_{D1}}{\mu_n C_{ox} \frac{W}{L}}} - \sqrt{\frac{2I_{D2}}{\mu_n C_{ox} \frac{W}{L}}}$$

$$\frac{\frac{1}{2}\mu_n C_{ox} \frac{W}{L} (V_{in1} - V_{in2})^2 - I_{SS} = -2\sqrt{I_{D1}I_{D2}}}{=K}$$

$$4I_{D1}I_{D2} = I_{SS}^{2} - 2I_{SS}K_{n}\Delta V_{in}^{2} + K_{n}^{2}\Delta V_{in}^{4}, \ \Delta V_{in} = V_{in1} - V_{in2}$$

$$4I_{D1}I_{D2} = (I_{D1} + I_{D2})^{2} - (I_{D1} - I_{D2})^{2} = I_{SS}^{2} - (I_{D1} - I_{D2})^{2}.$$

$$(I_{D1} - I_{D2})^{2} = I_{SS}^{2} - 4I_{D1}I_{D2}$$
$$= -K_{n}^{2}\Delta V_{in}^{4} + 2I_{SS}K_{n}\Delta V_{in}^{2}$$

$$(I_{D1} - I_{D2})^2 = -\frac{1}{4} \left(\mu_n C_{ox} \frac{W}{L} \right)^2 (V_{in1} - V_{in2})^4 + I_{SS} \mu_n C_{ox} \frac{W}{L} (V_{in1} - V_{in2})^4$$

$$I_{D1} - I_{D2} = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{in1} - V_{in2}) \sqrt{\frac{4I_{SS}}{\mu_n C_{ox} \frac{W}{L}} - (V_{in1} - V_{in2})^2}$$

$$= \sqrt{\mu_n C_{ox} \frac{W}{L} I_{SS} (V_{in1} - V_{in2})} \sqrt{1 - \frac{\mu_n C_{ox} (W/L)}{4 I_{SS}} (V_{in1} - V_{in2})^2}$$

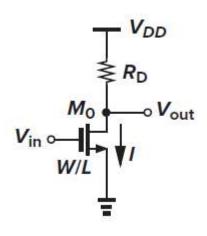


$$\frac{\partial \Delta I_D}{\partial \Delta V_{in}} = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} \frac{\frac{4I_{SS}}{\mu_n C_{ox} W/L} - 2\Delta V_{in}^2}{\sqrt{\frac{4I_{SS}}{\mu_n C_{ox} W/L} - \Delta V_{in}^2}}$$

Harmonic Distortion

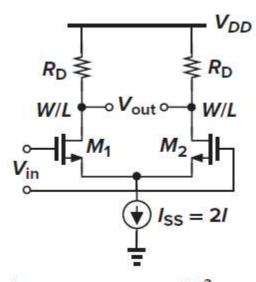
if
$$V_m = 0.2(V_{GS} - V_{TH})$$
,

Single-ended



$$\frac{A_{HD2}}{A_F} = \frac{V_m}{4(V_{GS} - V_{TH})}$$
$$= 5\%$$

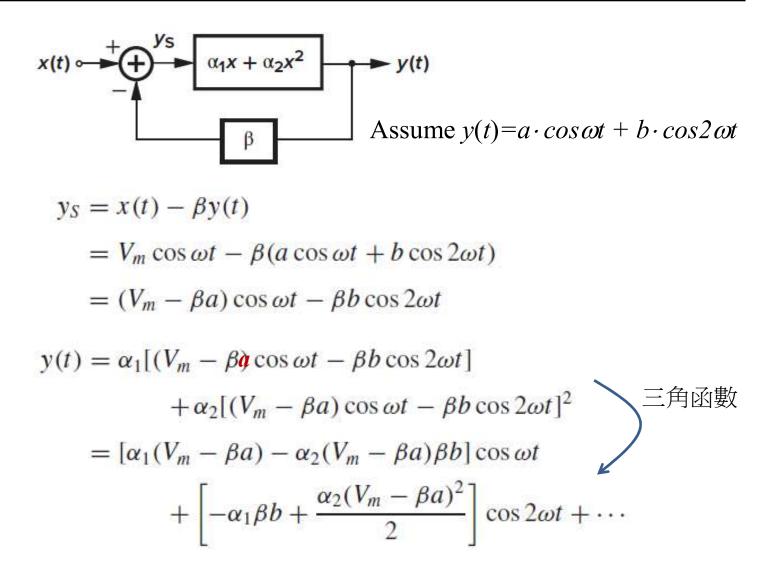
Fully differential



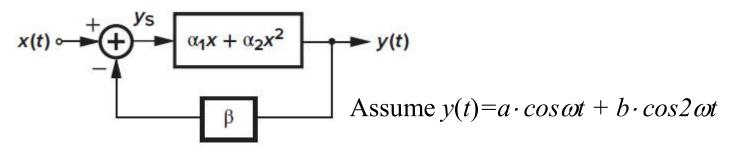
$$\frac{A_{HD3}}{A_F} \approx \frac{V_m^2}{32(V_{GS} - V_{TH})^2}$$
= 0.125%

Keep in mind: How to maintain the advantages of fully differential amplifiers?

Feedback on THD



Feedback on THD



$$y(t) = a\cos(\omega t) + b\cos(2\omega t)$$

$$a = (\alpha_1 - \alpha_2 \beta b)(V_m - \beta a)$$

$$b = -\alpha_1 \beta b + \frac{\alpha_2 (V_m - \beta a)^2}{2}$$

 $a \approx \alpha_1(V_m - \beta a)$ If α_2 and b are small

$$a = \frac{\alpha_1}{1 + \beta \alpha_1} V_m$$

To calculate b, we write

$$V_m - \beta a \approx \frac{a}{\alpha_1}$$

$$b = -\alpha_1 \beta b + \frac{1}{2} \alpha_2 \left(\frac{a}{\alpha_1}\right)^2$$

$$b(1 + \alpha_1 \beta) = \frac{\alpha_2}{2} \left(\frac{a}{\alpha_1}\right)^2$$
$$= \frac{\alpha_2}{2\alpha_1^2} \frac{\alpha_1^2}{(1 + \beta\alpha_1)^2} V_m^2$$

$$b = \frac{\alpha_2 V_m^2}{2} \frac{1}{(1 + \beta \alpha_1)^3}$$

$$\frac{b}{a} = \frac{\alpha_2 V_m}{2} \frac{1}{\alpha_1} \frac{1}{(1 + \beta \alpha_1)^2}$$

Improved by feedback

Linearization Technique (1)

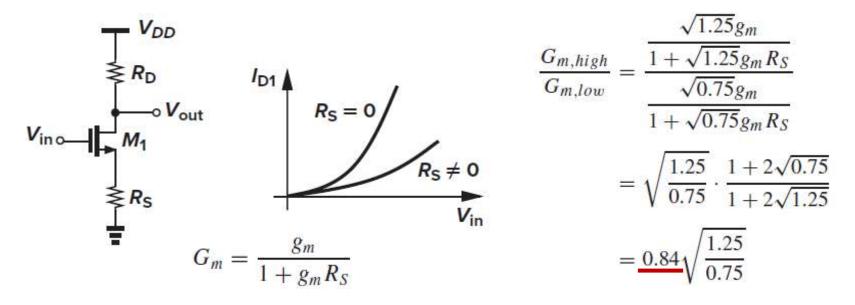
A common-source stage biased at a current I_1 experiences an input voltage swing that varies the drain current from $0.75I_1$ to $1.25I_1$. Calculate the variation of the small-signal voltage gain (a) with no degeneration and (b) with degeneration such that $g_m R_S = 2$, where g_m denotes the transconductance at $I_D = I_1$.

[Solution]

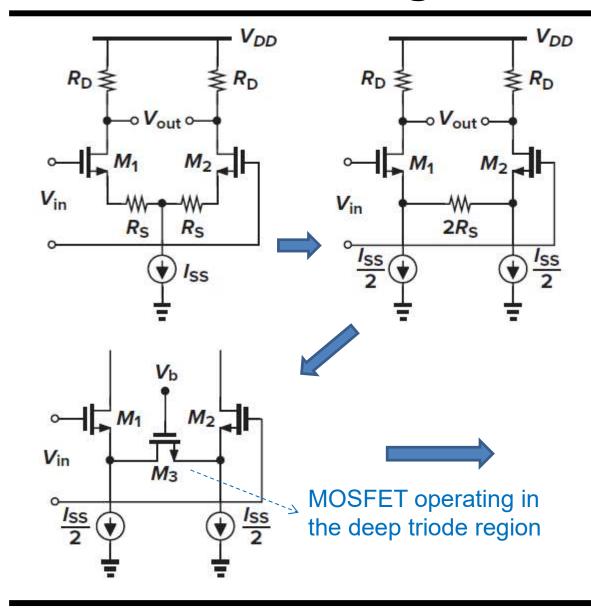
Assuming square-law behavior, we have $g_m \propto \sqrt{I_D}$. For the case of no degeneration,

$$\frac{g_{m,high}}{g_{m,low}} = \sqrt{\frac{1.25}{0.75}}$$

With $g_m R_S = 2$, (actually, too small)



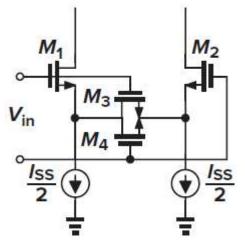
SCP Degeneration



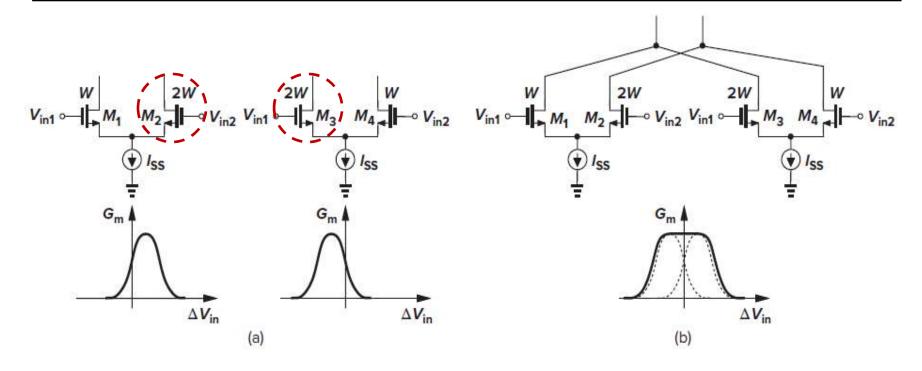
SCP: Source Couple Pair

$$G_m = \frac{g_m}{1 + g_m R_S}$$

Vb is applied as an input–tracking control



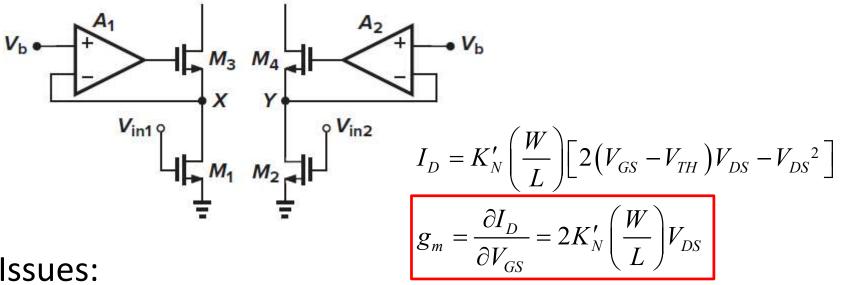
Linearization Technique (2)



- Shift g_m by changing the input pair into unbalance conditions: left-shift and right-shift
- The composite final g_m has a flat shape if the optimal design is achieved
- Issue is the g_m flatness is PVT-sensitive

Linearization Technique (3)

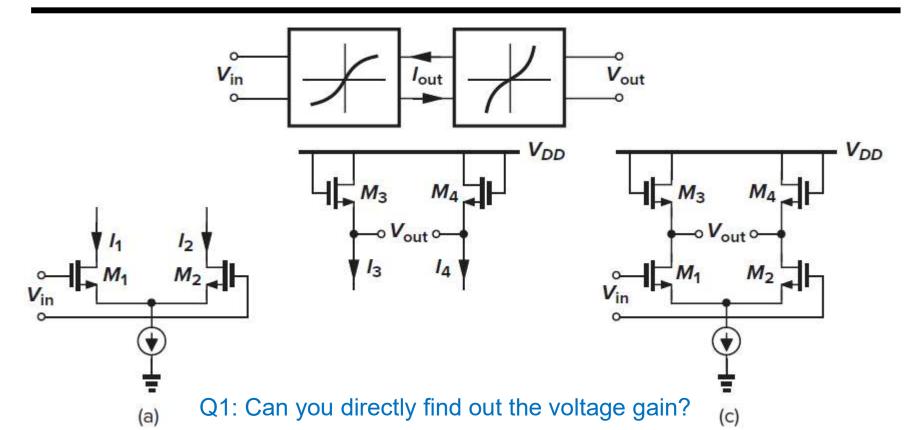
Differential pair using input devices operating in the triode region



Issues:

- V_{DS} must be low enough to ensure that each input transistor remains in the triode region
- The input common-mode level must be tightly controlled, and it must track V_h so as to define I_{D1} and I_{D2}
- Additional noise contribution from M3, M4, and two amplifiers
- g_m may be too small since V_{DS} is small

Linearization Technique (4)



Q2: How does it achieve the linearization?

$$\Delta I = I_1 - I_2 = g_{m1,2} \Delta V_{in} \qquad \Delta V_{out} = \frac{\Delta I}{g_{m3,4}} \qquad \Delta V_{out} = \frac{g_{m1,2}}{g_{m3,4}} \Delta V_{in}$$

Linearization Technique (4)

$$V_{in1} - V_{in2} = V_{GS1} - V_{GS2}$$

$$= \sqrt{\frac{2I_{D1}}{\mu_n C_{ox} \left(\frac{W}{L}\right)_{1,2}}} - \sqrt{\frac{2I_{D2}}{\mu_n C_{ox} \left(\frac{W}{L}\right)_{1,2}}}$$

$$V_{out} = V_{GS3} - V_{GS4}$$

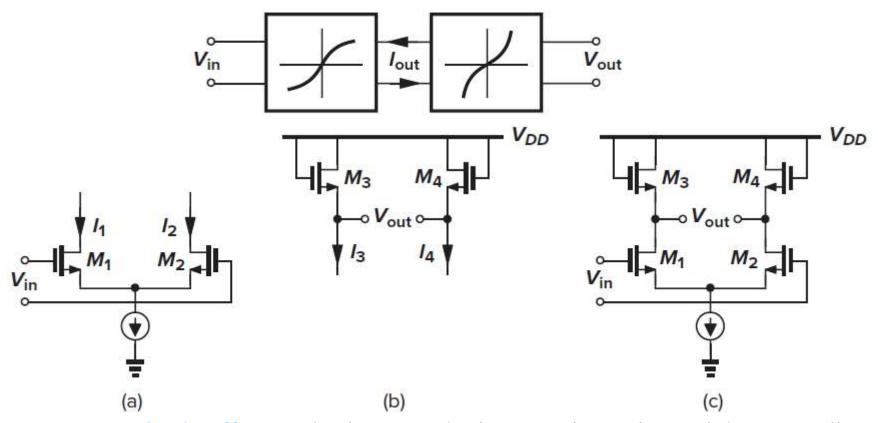
$$= \sqrt{\frac{2I_3}{\mu_n C_{ox} \left(\frac{W}{L}\right)_{3,4}}} - \sqrt{\frac{2I_4}{\mu_n C_{ox} \left(\frac{W}{L}\right)_{3,4}}}$$

$$V_{out} = \sqrt{\frac{2I_{D1}}{\mu_n C_{ox} \left(\frac{W}{L}\right)_{3,4}}} - \sqrt{\frac{2I_{D2}}{\mu_n C_{ox} \left(\frac{W}{L}\right)_{3,4}}}$$

$$= \frac{1}{\sqrt{\left(\frac{W}{L}\right)_{3,4}}} (V_{in1} - V_{in2}) \ sqrt\left(\frac{W}{L}\right)_{1,2}$$

$$A_v = \sqrt{\frac{W}{L}}_{3,4}$$

Linearization Technique (4)



- •In practice, **body effect** and other nonidealities in short-channel devices will further give rise to nonlinearity in this circuit.
- •Furthermore, as the differential input level increases, driving *M1 or M2* into the triode region, the linearization is no longer hold and the gain drops sharply => Body effect can be solved by deep-nwell nMOSTs

Linearization Technique (5)

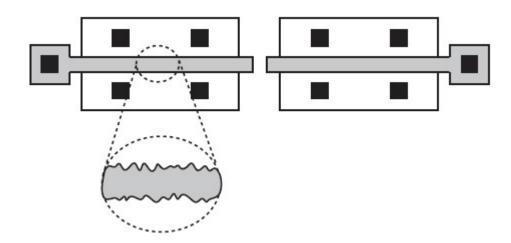
Local Feedback Network V_{DD} $V_{I3} \stackrel{\bullet}{\Downarrow} I_{4}$ $V_{IM1} \stackrel{\bullet}{\smile} I_{4}$ $V_{Im1} \stackrel{\bullet}{\smile} I_{2}$ $V_{Im1} \stackrel{\bullet}{\smile} I_{2}$

$$\begin{aligned} V_{in1} &= V_{cm} + V_{in} / 2 \\ V_{in2} &= V_{cm} - V_{in} / 2 \\ V_{in} &= V_{GS1} + I_{sig} R_S - V_{GS2} \\ &= I_{sig} R_S, \text{ if } \underline{V_{GS1}} = V_{GS2} \end{aligned}$$

where
$$I_3 = I_4$$
, $I_1 = I_3 + I_{M3}$; $I_2 = I_4 + I_{M4}$

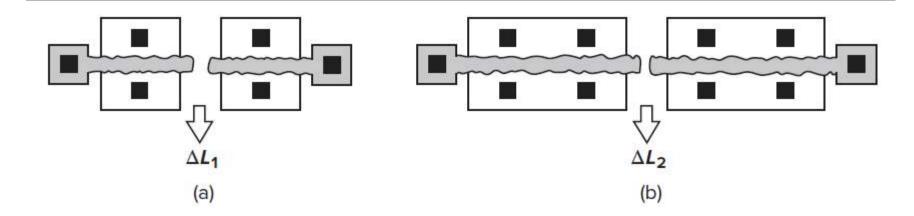
$$V_{out} = (I_6 - I_5)R_D$$
 $I_5 = I_{M4} \text{ and } I_6 = I_{M3}$
 $V_{out} = (I_{M3} - I_{M4})R_D$
 $= I_{sig}R_D = \frac{R_D}{R_S}V_{in}$

Mismatch



- Random mismatches due to microscopic variations in device dimensions(來自晶圓廠,在晶片製造上的非理想因素)
- Study of mismatch consists of two steps:
 - (1) To identify and formulate the mechanisms that lead to mismatch between devices, but it is not an easy work. Generally, it depends on the Foundry's process quality control
 - (2) To analyze the effect of device mismatches upon the performance of circuits

Mismatch

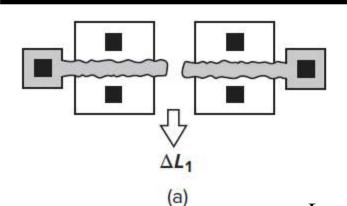


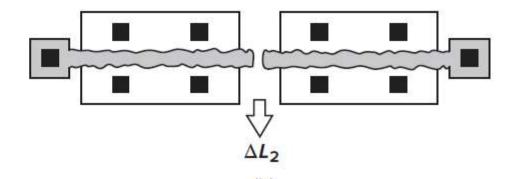
$$I_D = \frac{1}{2} \mu_n C_{ox} \left(\frac{W}{L}\right) \left(V_{GS} - V_{TH}\right)^2$$

Mismatch issue on

- Current mirrors
- Bias voltages
- For two nominally-identical transistors
- Mismatches of $\mu_n C_{ox}$, W, L, and V_{TH} result in mismatches between drain currents (for a given V_{GS}) or gate-source voltages (for a given drain current)
- Intuitively, larger devices exhibit smaller mismatches

Mismatch - Concept



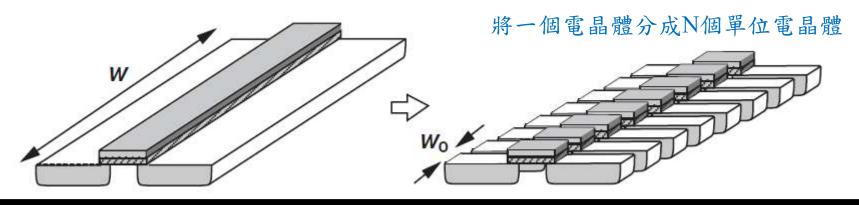


考量通道長度(L)的變異: $L_i = L_0 + \Delta L_i$ is a random variable

$$L_{eq} \approx \left(L_1 + L_2 + \dots + L_N\right) / N$$

$$\Delta L_{eq} \approx \frac{\sqrt{\Delta L_1^2 + \Delta L_2^2 + \dots + \Delta L_N^2}}{N} = \frac{\sqrt{N\Delta L_0^2}}{N} = \frac{\Delta L_0}{\sqrt{N}}$$

where ΔL_0 is the statistical variation of the length for a transistor with the length of L_0



Random Variables

Assume x_i is a zero mean random variable which is independent to each other

$$E[x_i] = 0$$
, and $E[x_i^2] = \sigma^2$, $\forall i$

Assume a function $y = x_1 + x_2 + x_3 + x_4$,

$$E[y] = E[x_1] + E[x_2] + E[x_3] + E[x_4] = 0$$

$$\sigma_y^2 = E[y^2] = E[x_1^2] + E[x_2^2] + E[x_3^2] + E[x_4^2] = 4\sigma^2$$

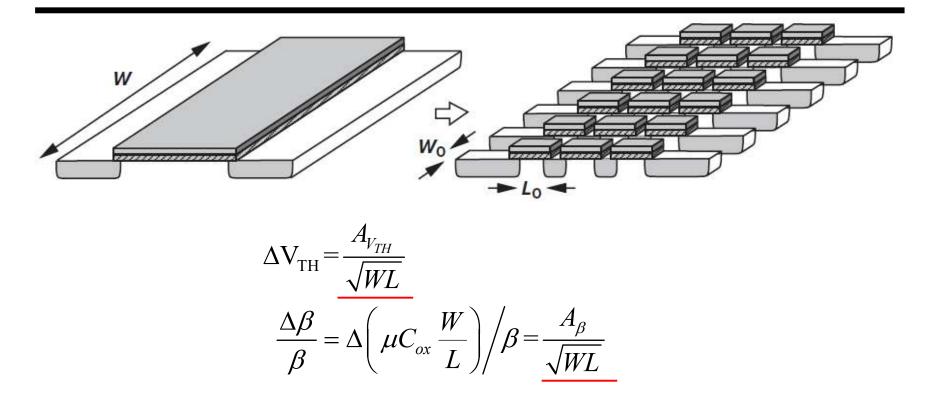
$$\Rightarrow \sigma_y = 2\sigma$$

Considering two new random variables,

$$y_1 = \sum_{i=1}^{N} x_i \Rightarrow \sigma_{y_1} = \sqrt{N}\sigma$$

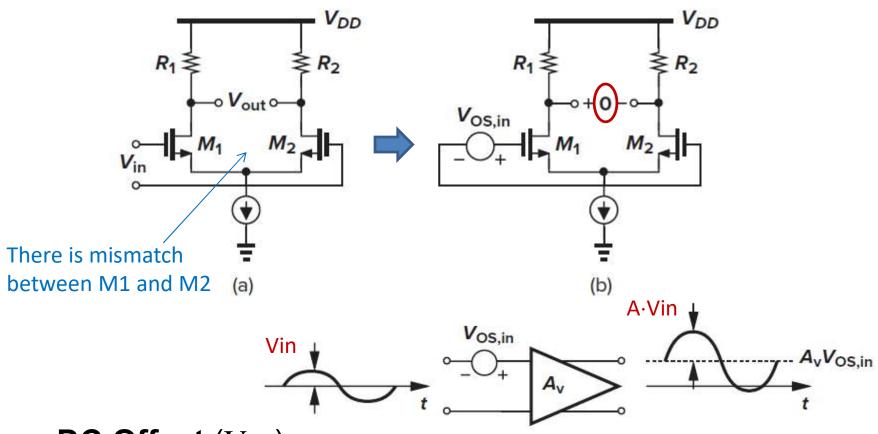
$$y_2 = \frac{1}{N} \sum_{i=1}^{N} x_i \Rightarrow \sigma_{y_2}^2 = \frac{1}{N^2} \sum_{i=1}^{N} E[x_i^2] = \frac{\sigma^2}{N} \Rightarrow \sigma_{y_2} = \frac{\sigma}{\sqrt{N}}$$

Mismatch



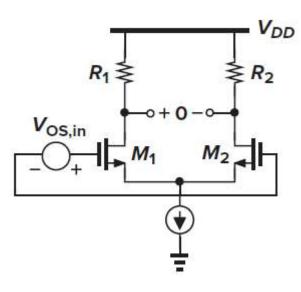
- We postulate that $\beta = \mu C_{ox}(W/L)$ and V_{TH} suffer from less mismatch if the device area increases (larger transistor dimension)
- For given W_0 and L_0 , as the number of unit transistors increases, β and V_{TH} experience greater averaging, leading to smaller mismatch between two large transistors

Mismatch of Input Pair



- DC Offset (V_{OS})
 - Two conditions: (1) Vin=0 but Vout≠0; (2) Vin≠0 but Vout=0
 - Figure (b) presents the input-referred offset voltage ($V_{\rm OS,in}$), caused by the device mismatch

Input-Referred Offset



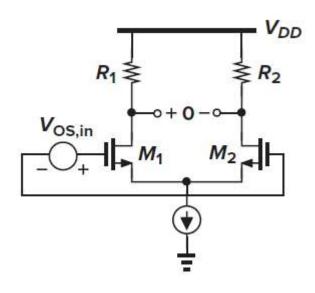
$$\begin{split} &V_{TH1} = V_{TH}, \ V_{TH2} = V_{TH} + \Delta V_{TH} \\ &\left(\frac{W}{L}\right)_{1} = \frac{W}{L}, \left(\frac{W}{L}\right)_{2} = \frac{W}{L} + \Delta \left(\frac{W}{L}\right) \\ &R_{1} = R_{D}, \ R_{2} = R_{D} + \Delta R \\ &\text{Assume } \lambda = \gamma = 0, \ \Delta \left(\mu_{n} C_{ox}\right) = 0 \\ &V_{out} = 0, \ I_{D1} R_{1} = I_{D2} R_{2} \\ &I_{D1} = I_{D}, \ I_{D2} = I_{D} + \Delta I_{D} \end{split}$$

$$\begin{split} V_{OS,in} &= V_{GS1} - V_{GS2} \\ &= \sqrt{\frac{2I_{D1}}{\mu_n C_{ox}} \left(\frac{W}{L}\right)_1} + V_{TH1} - \sqrt{\frac{2I_{D2}}{\mu_n C_{ox}} \left(\frac{W}{L}\right)_2} - V_{TH2} \\ &= \sqrt{\frac{2}{\mu_n C_{ox}}} \left[\sqrt{\frac{I_D}{W/L}} - \sqrt{\frac{I_D + \Delta I_D}{W/L + \Delta (W/L)}} \right] - \Delta V_{TH} \\ &= \sqrt{\frac{2I_D}{\mu_n C_{ox}} \left(W/L\right)} \left[1 - \sqrt{\frac{1 + \Delta I_D/I_D}{1 + \Delta (W/L)/(W/L)}} \right] - \Delta V_{TH} \end{split}$$

Assume $\Delta I_D/I_D$ and $\Delta (W/L)/(W/L) \ll 1$,

$$\begin{split} &\text{for } \varepsilon \! \not \in \! 1, \sqrt{1 + \varepsilon} \approx 1 + \varepsilon/2 \\ &V_{OS,in} = \sqrt{\frac{2I_D}{\mu_n C_{ox} \left(W/L\right)}} \left\{ 1 - \left(1 + \frac{\Delta I_D}{2I_D}\right) \left(1 - \frac{\Delta \left(W/L\right)}{2\left(W/L\right)}\right) \right\} - \Delta V_{TH} \\ &V_{OS,in} = \sqrt{\frac{2I_D}{\mu_n C_{ox} \left(W/L\right)}} \left[\frac{-\Delta I_D}{2I_D} + \frac{\Delta \left(W/L\right)}{2\left(W/L\right)} \right] - \Delta V_{TH} \end{split}$$

Input-Referred Offset



$$\begin{split} \Delta I_D/I_D &\approx -\Delta R_D/R_D \\ V_{OS,in} &= \frac{1}{2} \sqrt{\frac{2I_D}{\mu_n C_{ox} \left(W/L\right)}} \left[\frac{\Delta R_D}{R_D} + \frac{\Delta \left(W/L\right)}{\left(W/L\right)} \right] - \Delta V_{TH} \\ &= \frac{V_{GS} - V_{TH}}{2} \left[\frac{\Delta R_D}{R_D} + \frac{\Delta \left(W/L\right)}{\left(W/L\right)} \right] - \Delta V_{TH} \end{split}$$

 $=>V_{OS.in}$ is also a random variable

$$\begin{split} V_{OS,in}^2 &= \left(\frac{V_{GS} - V_{TH}}{2}\right)^2 \left[\left(\frac{\Delta R_D}{R_D}\right)^2 + \left(\frac{\Delta \left(W/L\right)}{\left(W/L\right)}\right)^2 \right] + \Delta V_{TH}^2 \\ \sigma_{OS,in}^2 &= \left(\frac{V_{GS} - V_{TH}}{2}\right)^2 \left[\sigma \left(\frac{\Delta R_D}{R_D}\right)^2 + \sigma \left(\frac{\Delta \left(W/L\right)}{\left(W/L\right)}\right)^2 \right] + \sigma_{V_{TH}}^2 \end{split}$$

Q: From this result, to get a small offset, how to design V_{GS} - V_{TH} ?

Mismatch of Current Mirror

Recall
$$y = f\left(x_{1}, x_{2}, ...\right)$$

$$\Delta y = \frac{\partial f}{\partial x_{1}} \Delta x_{1} + \frac{\partial f}{\partial x_{2}} \Delta x_{2} + \cdots$$

$$\Delta I_{D} = \frac{\partial I_{D}}{\partial \left(W/L\right)} \Delta \left(\frac{W}{L}\right) + \frac{\partial I_{D}}{\partial \left(V_{GS} - V_{TH}\right)} \Delta \left(V_{GS} - V_{TH}\right)$$

$$\Delta I_{D} = \frac{1}{2} \mu_{n} C_{ox} \left(V_{GS} - V_{TH}\right)^{2} \Delta \left(\frac{W}{L}\right) - \mu_{n} C_{ox} \left(\frac{W}{L}\right) \left(V_{GS} - V_{TH}\right) \Delta V_{TH}$$

$$\frac{\Delta I_{D}}{I_{D}} = \frac{\Delta \left(W/L\right)}{W/L} - \left(\frac{V_{GS} - V_{TH}}{2}\right)^{-1} \Delta V_{TH}$$

 Different from V_{OS,in}, the current mismatch is inversely proportional to gate-overdrive voltage (V_{GS}-V_{TH})

Even-Order Distortion: Mismatch

$$x_{1}(t) \circ y_{1}(t)$$

$$x_{2}(t) \circ y_{2}(t)$$

$$\beta_{1}x + \beta_{2}x^{2} + \beta_{3}x^{3}$$

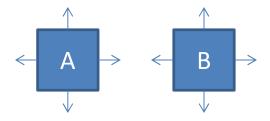
$$y_{1} - y_{2} = (\alpha_{1}x_{1} - \beta_{1}x_{2}) + (\alpha_{2}x_{1}^{2} - \beta_{2}x_{2}^{2}) + (\alpha_{3}x_{1}^{3} - \beta_{3}x_{2}^{3})$$
Assume $x_{1} = x$ and $x_{2} = -x$,
if $\alpha_{i} \neq \beta_{i}$, $\forall i$

$$y_{d} = y_{1} - y_{2} = (\alpha_{1} + \beta_{1})x + (\alpha_{2} - \beta_{2})x^{2} + (\alpha_{3} + \beta_{3})x^{3}$$

- Single-ended signals have tones of 2nd, 3rd, 4th, ...
- Fully differential circuits ideally have only odd-order tones
- However, mismatch causes even-order tones in differential signals
- In addition, the (thermal) gradient also contributes mismatch

Gradient: Systematic Issue

Random mismatch

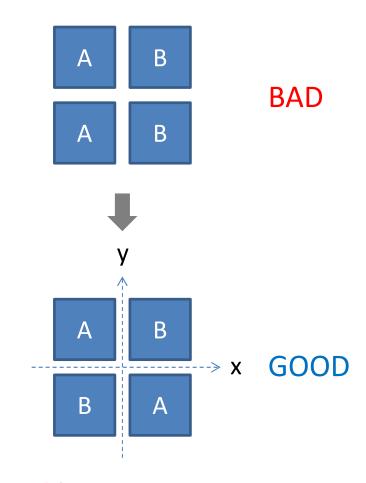


Thermal gradient



Gradient is a deterministic error which causes additional mismatch errors

Layout pattern for gradient

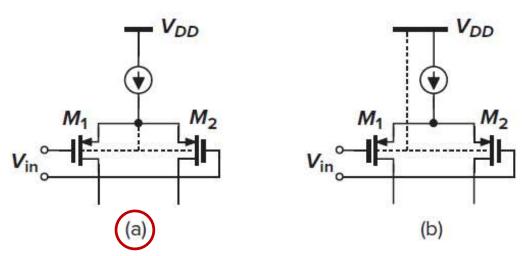


The solution is **common-centroid** layout patterns

CMRR Considerations

$$A_{CM-DM} = \frac{\Delta V_{OS,out}}{\Delta V_{CM,in}}, \ A_{DM} = \frac{\Delta V_{OS,out}}{\Delta V_{OS,in}}$$

$$CMRR = \frac{A_{DM}}{A_{CM-DM}} = \frac{A_{DM}}{\frac{\Delta V_{OS,out}}{\Delta V_{CM,in}}} = \frac{\Delta V_{CM,in}}{\frac{\Delta V_{OS,out}}{A_{DM}}} = \frac{\Delta V_{CM,in}}{\frac{\Delta V_{OS,out}}{A_{DM}}}$$
 Less mismatch, higher CMRR



In Fig. (a), body effect is eliminated and the threshold voltages of M1 and M2 are independent of the input CM level. But, large layout area is introduced!!

In Fig. (b), if they suffer from mismatches in their body effect coefficients, the input offset voltage varies with the input CM level